



MICROCHIP

QUALIFICATION REPORT SUMMARY

PCN #: MFOL-01TAEI708

Date:

February 18, 2026

Qualification of AMK-06 as a new die attach material for AT25080B-MAHL-E, AT25080B-MAHL-T, AT25160B-MAHL-E, and AT25160B-MAHL-T catalog part numbers (CPN) available in 8L UDFN (2x3x0.6mm) package at ATP7 assembly site will qualify by similarity (QBS).



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PACKAGE QUALIFICATION REPORT

Purpose: Qualification of AMK-06 as a new die attach material for AT25080B-MAHL-E, AT25080B-MAHL-T, AT25160B-MAHL-E, and AT25160B-MAHL-T catalog part numbers (CPN) available in 8L UDFN (2x3x0.6mm) package at ATP7 assembly site will qualify by similarity (QBS).

CCB No. 3689 and 8127

<u>Misc.</u>	Assembly site	ATP7
	BD Number	BD-003881-01
	MP Code (MPC)	Various
	Part Number (CPN)	Various
	MSL information	1
<u>Lead-Frame</u>	Paddle size	79 x 67 mils
	Material	C7025
	DAP Surface Prep	PPF
	Treatment	Roughened
	Process	Etched
	Lead-lock	Yes
	Part Number	101376524
	Lead Plating	NiPdAu
	Strip Size	70 x 250 mm
	Strip Density	x1690
<u>Bond Wire</u>	Material	PdCu
<u>Die Attach</u>	Conductive	Yes
<u>MC</u>	Part Number	G700Y
<u>PKG</u>	Package Type	UDFN
	Pin/Ball Count	8
	PKG width/size	2 x 3 x 0.6 mm

Test Name	Test Method	Stress Test Conditions	Duration/ Read points	PreCond JESA113*	SS/Lot	Assembly Lot SMPCU626B	Assembly Lot SMPCU626C	Assembly Lot SMPCU626D
ESD HBM w_Cu Wire**	MilStd 883 Method 3015	25C	500V, 1k, 2k, 3k, 4k	NO	3 per Voltage	AT35830		
						Lot# DVS297C Pass 4000V	Lot# DVS297B Pass 4000V	Lot# DVS297D Pass 4000V
ESD HBM w_Au Wire**	MilStd 883 Method 3015	25C	500V, 1k, 2k, 3k, 4k	NO	3 per Voltage	AT35830 - Lot#9h0390 Pass - 4000V		
ESD MM W_Cu Wire**	JEDEC22 Method 115	25C	50V, 100V, 200V 300V, 400V	NO	3 per Voltage	AT35830		
						Lot# DVS297B Pass 400V	Lot# DVS297C Pass 200V 1	Lot# DVS297C Pass 300V 1
ESD MM w_Au Wire**	JEDEC22 Method 115	25C	50V, 100V, 200V 300V, 400V	NO	3 per Voltage	AT35830 - Lot#9h0390 Pass - 300V 2		
ESD CDM W_Cu Wire**	JEDEC22 Method C101	25C	50V, 100V, 200V 300V, 400V	NO	3 per Voltage	AT35830		
						Lot# DVS297B Pass 1000V	Lot# DVS297C Pass 1000V	Lot# DVS297D Pass 1000V
ESD CDM w_Au Wire**	JEDEC22 Method C101	25C	50V, 100V, 200V 300V, 400V	NO	3 per Voltage	AT35830 - Lot#9h0390 Pass 1000V		
High Temperature Storage	Unbiased Bake	150C - Unbiased	1008 Hours	NO	1000	Pass (986) 0 Failures	Pass (998) 0 Failures	Pass (974) 0 Failures
Extended HTS	Unbiased Bake	150C - Unbiased	1008 Hours (2016 Hrs Cum)	NO	1000	Pass (986) 0 Failures	Pass (998) 0 Failures	Pass (974) 0 Failures
HAST	JESD22A101B	130C/85%RH 5V - Static Bias	96 Hours	YES	77	Pass 0 Failures	Pass 0 Failures	Pass 0 Failures
Extended HAST	JESD22A101B	130C/85%RH 5V - Static Bias	96 Hours (192 Hrs Cum)	YES	77	Pass 0 Failures	Pass 0 Failures	Pass 0 Failures
Temperature Cycle	JESD22A104A	-65C/150C	500 Cycles	YES	1000	Pass (983) 0 Failures	Pass (998) 0 Failures	Pass (1k) 0 Failures
Autoclave	JESDA102B	100%RH/121C	96 Hours	YES	77	Pass 0 Failures	Pass 0 Failures	Pass 0 Failures